

Notice of References Cited

Application/Control No.

09/582,495

Applicant(s)/Patent Under
Reexamination
OHGA ET AL.

Examiner

Hector M Reyes

Art Unit

1623

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US- -			
	B	US- -			
	C	US- -			
	D	US- -			
	E	US- -			
	F	US- -			
	G	US- -			
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	I	US- -			
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	K	US- -			
	L	US- -			
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	N	JP-09194427-	07-1997	Japan	Takada et al	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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